

Title (en)

APPARATUS AND METHOD FOR INSPECTING MICROSTRUCTURES IN REFLECTED OR TRANSMITTED INFRARED LIGHT

Title (de)

VORRICHTUNG UND VERFAHREN ZUR OPTISCHEN AUF- UND/ODER DURCHLICHTINSPEKTION VON MIKROSTRUKTUREN IM IR

Title (fr)

DISPOSITIF ET PROCEDE D'INSPECTION OPTIQUE EN LUMIERE REFLECHIE ET/OU EN LUMIERE TRANSMISE DE MICROSTRUCTURES EN IR

Publication

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Application

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Abstract (en)

[origin: WO2005124422A1] Previously used examination devices and methods mostly operate with reflected visible or UV light to analyze microstructured samples of a wafer (38), for example. The aim of the invention is to increase the possible uses of said devices, i.e. particularly in order to represent structural details, e.g. of wafers that are structured on both sides, which are not visible in VIS or UV because coatings or intermediate materials are not transparent. Said aim is achieved by using IR light as reflected light while creating transillumination (52) which significantly improves contrast in the IR image, among other things, thus allowing the sample to be simultaneously represented in reflected or transmitted IR light and in reflected visible light.

IPC 8 full level

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